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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### Details

Product Status	Active
Number of LABs/CLBs	1139
Number of Logic Elements/Cells	14579
Total RAM Bits	589824
Number of I/O	186
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc6slx16-2ftg256i">https://www.e-xfl.com/product-detail/xilinx/xc6slx16-2ftg256i</a>

Table 1: Absolute Maximum Ratings<sup>(1)</sup> (Cont'd)

Symbol	Description				Units	
$V_{IN}$ and $V_{TS}$ <sup>(3)</sup>	I/O input voltage or voltage applied to 3-state output, relative to GND <sup>(4)</sup>	All user and dedicated I/Os	Commercial	DC	-0.60 to 4.10	V
				20% overshoot duration	-0.75 to 4.25	V
				8% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V
			Industrial	DC	-0.60 to 3.95	V
				20% overshoot duration	-0.75 to 4.15	V
				4% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V
			Expanded (Q)	DC	-0.60 to 3.95	V
				20% overshoot duration	-0.75 to 4.15	V
				4% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V
		Restricted to maximum of 100 user I/Os	Commercial	20% overshoot duration	-0.75 to 4.35	V
				15% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V
				10% overshoot duration	-0.75 to 4.45	V
			Industrial	20% overshoot duration	-0.75 to 4.25	V
				10% overshoot duration	-0.75 to 4.35	V
				8% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V
Expanded (Q)	20% overshoot duration	-0.75 to 4.25	V			
	10% overshoot duration	-0.75 to 4.35	V			
	8% overshoot duration <sup>(5)</sup>	-0.75 to 4.40	V			
$T_{STG}$	Storage temperature (ambient)				-65 to 150	°C
$T_{SOL}$	Maximum soldering temperature <sup>(6)</sup> (TQG144, CPG196, CSG225, CSG324, CSG484, and FTG256)				+260	°C
	Maximum soldering temperature <sup>(6)</sup> (Pb-free packages: FGG484, FGG676, and FGG900)				+250	°C
	Maximum soldering temperature <sup>(6)</sup> (Pb packages: CS484, FT256, FG484, FG676, and FG900)				+220	°C
$T_j$	Maximum junction temperature <sup>(6)</sup>				+125	°C

**Notes:**

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
2. When programming eFUSE,  $V_{FS} \leq V_{CCAUX}$ . Requires up to 40 mA current. For read mode,  $V_{FS}$  can be between GND and 3.45 V.
3. I/O absolute maximum limit applied to DC and AC signals. Overshoot duration is the percentage of a data period that the I/O is stressed beyond 3.45V.
4. For I/O operation, refer to [UG381](#): *Spartan-6 FPGA SelectIO Resources User Guide*.
5. Maximum percent overshoot duration to meet 4.40V maximum.
6. For soldering guidelines and thermal considerations, see [UG385](#): *Spartan-6 FPGA Packaging and Pinout Specification*.

Table 3: eFUSE Programming Conditions<sup>(1)</sup>

Symbol	Description	Min	Typ	Max	Units
$V_{FS}^{(2)}$	External voltage supply	3.2	3.3	3.4	V
$I_{FS}$	$V_{FS}$ supply current	–	–	40	mA
$V_{CCAUX}$	Auxiliary supply voltage relative to GND	3.2	3.3	3.45	V
$R_{FUSE}^{(3)}$	External resistor from $R_{FUSE}$ pin to GND	1129	1140	1151	$\Omega$
$V_{CCINT}$	Internal supply voltage relative to GND	1.14	1.2	1.26	V
$t_j$	Temperature range	15	–	85	$^{\circ}\text{C}$

**Notes:**

1. These specifications apply during programming of the eFUSE AES key. Programming is only supported through JTAG. The AES key is only supported in the following devices: LX75, LX75T, LX100, LX100T, LX150, and LX150T.
2. When programming eFUSE,  $V_{FS}$  must be less than or equal to  $V_{CCAUX}$ . When not programming or when eFUSE is not used, Xilinx recommends connecting  $V_{FS}$  to GND. However,  $V_{FS}$  can be between GND and 3.45 V.
3. An  $R_{FUSE}$  resistor is required when programming the eFUSE AES key. When not programming or when eFUSE is not used, Xilinx recommends connecting the  $R_{FUSE}$  pin to  $V_{CCAUX}$  or GND. However,  $R_{FUSE}$  can be unconnected.

Table 4: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ	Max	Units
$V_{DRINT}$	Data retention $V_{CCINT}$ voltage (below which configuration data might be lost)	0.8	–	–	V
$V_{DRAUX}$	Data retention $V_{CCAUX}$ voltage (below which configuration data might be lost)	2.0	–	–	V
$I_{REF}$	$V_{REF}$ leakage current per pin for commercial (C) and industrial (I) devices	–10	–	10	$\mu$ A
	$V_{REF}$ leakage current per pin for expanded (Q) devices	–15	–	15	$\mu$ A
$I_L$	Input or output leakage current per pin (sample-tested) for commercial (C) and industrial (I) devices	–10	–	10	$\mu$ A
	Input or output leakage current per pin (sample-tested) for expanded (Q) devices	–15	–	15	$\mu$ A
$I_{HS}$	Leakage current on pins during hot socketing with FPGA unpowered	–20	–	20	$\mu$ A
	All pins except PROGRAM_B, DONE, and JTAG pins when HSWAPEN = 1 PROGRAM_B, DONE, and JTAG pins, or other pins when HSWAPEN = 0	$I_{HS} + I_{RPU}$			$\mu$ A
$C_{IN}^{(1)}$	Die input capacitance at the pad	–	–	10	pF
$I_{RPU}$	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 3.3V$ or $V_{CCAUX} = 3.3V$	200	–	500	$\mu$ A
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 2.5V$ or $V_{CCAUX} = 2.5V$	120	–	350	$\mu$ A
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.8V$	60	–	200	$\mu$ A
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.5V$	40	–	150	$\mu$ A
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.2V$	12	–	100	$\mu$ A
$I_{RPD}$	Pad pull-down (when selected) @ $V_{IN} = V_{CCO}$ , $V_{CCAUX} = 3.3V$	200	–	550	$\mu$ A
	Pad pull-down (when selected) @ $V_{IN} = V_{CCO}$ , $V_{CCAUX} = 2.5V$	140	–	400	$\mu$ A
$I_{BATT}^{(2)}$	Battery supply current	–	–	150	nA
$R_{DT}^{(3)}$	Resistance of optional input differential termination circuit, $V_{CCAUX} = 3.3V$	–	100	–	$\Omega$
$R_{IN\_TERM}^{(5)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_25) for commercial (C) and industrial (I) devices	23	25	55	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_25) for expanded (Q) devices	20	25	55	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_50) for commercial (C) and industrial (I) devices	39	50	72	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_50) for expanded (Q) devices	32	50	74	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_75) for commercial (C) and industrial (I) devices	56	75	109	$\Omega$
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}$ (UNTUNED_SPLIT_75) for expanded (Q) devices	47	75	115	$\Omega$
$R_{OUT\_TERM}$	Thevenin equivalent resistance of programmable output termination (UNTUNED_25)	11	25	52	$\Omega$
	Thevenin equivalent resistance of programmable output termination (UNTUNED_50)	21	50	96	$\Omega$
	Thevenin equivalent resistance of programmable output termination (UNTUNED_75)	29	75	145	$\Omega$

**Notes:**

1. The  $C_{IN}$  measurement represents the die capacitance at the pad, not including the package.
2. Maximum value specified for worst case process at 25°C. LX75, LX75T, LX100, LX100T, LX150, and LX150T only.
3. Refer to IBIS models for  $R_{DT}$  variation and for values at  $V_{CCAUX} = 2.5V$ . IBIS values for  $R_{DT}$  are valid for all temperature ranges.
4.  $V_{CCO2}$  is not required for data retention. The minimum  $V_{CCO2}$  for power-on reset and configuration is 1.65V.
5. Termination resistance to a  $V_{CCO}/2$  level.

Table 14: GTP Transceiver Current Supply (per Lane)

Symbol	Description	Typ <sup>(1)</sup>	Max	Units
I <sub>MGTAVCC</sub>	GTP transceiver internal analog supply current	40.4	Note 2	mA
I <sub>MGTAVTTTX</sub>	GTP transmitter termination supply current	27.4		mA
I <sub>MGTAVTTRX</sub>	GTP receiver termination supply current	13.6		mA
I <sub>MGTAVCCPLL</sub>	GTP transmitter and receiver PLL supply current	28.7		mA
R <sub>MGTRREF</sub>	Precision reference resistor for internal calibration termination	50.0 ± 1% tolerance		Ω

**Notes:**

1. Typical values are specified at nominal voltage, 25°C, with a 2.5 Gb/s line rate, with a shared PLL use mode.
2. Values for currents of other transceiver configurations and conditions can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

 Table 15: GTP Transceiver Quiescent Supply Current (per Lane)<sup>(1)(2)(3)(4)</sup>

Symbol	Description	Typ <sup>(5)</sup>	Max	Units
I <sub>MGTAVCCQ</sub>	Quiescent MGTAVCC supply current	1.7	Note 2	mA
I <sub>MGTAVTTTXQ</sub>	Quiescent MGTAVTTTX supply current	0.1		mA
I <sub>MGTAVTTRXQ</sub>	Quiescent MGTAVTTRX supply current	1.2		mA
I <sub>MGTAVCCPLLQ</sub>	Quiescent MGTAVCCPLL supply current	1.0		mA

**Notes:**

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.
3. GTP transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTP transceivers.
4. Does not include power-up MGTAVTTRCAL supply current during device configuration.
5. Typical values are specified at nominal voltage, 25°C.

Table 21: GTP Transceiver User Clock Switching Characteristics<sup>(1)</sup>

Symbol	Description	Conditions	Speed Grade				Units
			-3	-3N	-2	-1L	
F <sub>TXOUT</sub>	TXOUTCLK maximum frequency		320	320	270	N/A	MHz
F <sub>RXREC</sub>	RXRECCLK maximum frequency		320	320	270	N/A	MHz
T <sub>RX</sub>	RXUSRCLK maximum frequency		320	320	270	N/A	MHz
T <sub>RX2</sub>	RXUSRCLK2 maximum frequency	1 byte interface	156.25	156.25	125	N/A	MHz
		2 byte interface	160	160	125	N/A	MHz
		4 byte interface	80	80	67.5	N/A	MHz
T <sub>TX</sub>	TXUSRCLK maximum frequency		320	320	270	N/A	MHz
T <sub>TX2</sub>	TXUSRCLK2 maximum frequency	1 byte interface	156.25	156.25	125	N/A	MHz
		2 byte interface	160	160	125	N/A	MHz
		4 byte interface	80	80	67.5	N/A	MHz

Notes:

1. Clocking must be implemented as described in [UG386: Spartan-6 FPGA GTP Transceivers User Guide](#).

Table 22: GTP Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T <sub>RTX</sub>	TX Rise time	20%–80%	–	140	–	ps
T <sub>FTX</sub>	TX Fall time	80%–20%	–	120	–	ps
T <sub>LLSKEW</sub>	TX lane-to-lane skew <sup>(1)</sup>		–	–	400	ps
V <sub>TXOOBVDPP</sub>	Electrical idle amplitude		–	–	20	mV
T <sub>TXOOBTRANSITION</sub>	Electrical idle transition time		–	–	50	ns
T <sub>J3.125</sub>	Total Jitter <sup>(2)</sup>	3.125 Gb/s	–	–	0.35	UI
D <sub>J3.125</sub>	Deterministic Jitter <sup>(2)</sup>		–	–	0.15	UI
T <sub>J2.5</sub>	Total Jitter <sup>(2)</sup>	2.5 Gb/s	–	–	0.33	UI
D <sub>J2.5</sub>	Deterministic Jitter <sup>(2)</sup>		–	–	0.15	UI
T <sub>J1.62</sub>	Total Jitter <sup>(2)</sup>	1.62 Gb/s	–	–	0.20	UI
D <sub>J1.62</sub>	Deterministic Jitter <sup>(2)</sup>		–	–	0.10	UI
T <sub>J1.25</sub>	Total Jitter <sup>(2)</sup>	1.25 Gb/s	–	–	0.20	UI
D <sub>J1.25</sub>	Deterministic Jitter <sup>(2)</sup>		–	–	0.10	UI
T <sub>J614</sub>	Total Jitter <sup>(2)</sup>	614 Mb/s	–	–	0.10	UI
D <sub>J614</sub>	Deterministic Jitter <sup>(2)</sup>		–	–	0.05	UI

Notes:

1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to four consecutive GTP transceiver sites.
2. Using PLL\_DIVSEL\_FB = 2, INTDATAWIDTH = 1. These values are NOT intended for protocol specific compliance determinations.

Table 23: GTP Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units	
T <sub>RXELECIDLE</sub>	Time for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns	
R <sub>XOOBVDPP</sub>	OOB detect threshold peak-to-peak		60	–	150	mV	
R <sub>XSSST</sub>	Receiver spread-spectrum tracking <sup>(1)</sup>	Modulated @ 33 KHz	–5000	–	0	ppm	
R <sub>XRL</sub>	Run length (CID)	Internal AC capacitor bypassed	–	–	150	UI	
R <sub>XPPMTOL</sub>	Data/REFCLK PPM offset tolerance	CDR 2 <sup>nd</sup> -order loop disabled	–200	–	200	ppm	
		CDR 2 <sup>nd</sup> -order loop enabled	PLL_RXDIVSEL_OUT = 1	–2000	–	2000	ppm
			PLL_RXDIVSEL_OUT = 2	–2000	–	2000	ppm
		PLL_RXDIVSEL_OUT = 4	–1000	–	1000	ppm	
<b>SJ Jitter Tolerance<sup>(2)</sup></b>							
JT_SJ <sub>3.125</sub>	Sinusoidal Jitter <sup>(3)</sup>	3.125 Gb/s	0.4	–	–	UI	
JT_SJ <sub>2.5</sub>	Sinusoidal Jitter <sup>(3)</sup>	2.5 Gb/s	0.4	–	–	UI	
JT_SJ <sub>1.62</sub>	Sinusoidal Jitter <sup>(3)</sup>	1.62 Gb/s	0.5	–	–	UI	
JT_SJ <sub>1.25</sub>	Sinusoidal Jitter <sup>(3)</sup>	1.25 Gb/s	0.5	–	–	UI	
JT_SJ <sub>614</sub>	Sinusoidal Jitter <sup>(3)</sup>	614 Mb/s	0.5	–	–	UI	
<b>SJ Jitter Tolerance with Stressed Eye<sup>(2)(5)</sup></b>							
JT_TJSE <sub>3.125</sub>	Total Jitter with stressed eye <sup>(4)</sup>	3.125 Gb/s	0.65	–	–	UI	
JT_SJSE <sub>3.125</sub>	Sinusoidal Jitter with stressed eye	3.125 Gb/s	0.1	–	–	UI	
JT_TJSE <sub>2.7</sub>	Total Jitter with stressed eye <sup>(4)</sup>	2.7 Gb/s	0.65	–	–	UI	
JT_SJSE <sub>2.7</sub>	Sinusoidal Jitter with stressed eye	2.7 Gb/s	0.1	–	–	UI	

**Notes:**

- Using PLL\_RXDIVSEL\_OUT = 1, 2, and 4.
- All jitter values are based on a Bit Error Ratio of 1e<sup>-12</sup>.
- Using 80 MHz sinusoidal jitter only in the absence of deterministic and random jitter.
- Composed of 0.37 UI DJ in the form of ISI and 0.18 UI RJ.
- Measured using PRBS7 data pattern.

## Endpoint Block for PCI Express Designs Switching Characteristics

The Endpoint block for PCI Express is available in the Spartan-6 LXT devices. Consult the [Spartan-6 FPGA Integrated Endpoint Block for PCI Express](#) for further information.

Table 24: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F <sub>PCIEUSER</sub>	User clock maximum frequency	62.5	62.5	62.5	N/A	MHz

## Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases. [Table 27](#) lists the production released Spartan-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE® software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

*Table 27: Spartan-6 Device Production Software and Speed Specification Release<sup>(1)</sup>*

Device	Speed Grade Designations <sup>(2)</sup>			
	-3 <sup>(3)</sup>	-3N	-2 <sup>(4)</sup>	-1L
XC6SLX4	ISE 12.4 v1.15	N/A	ISE 12.3 v1.12 <sup>(5)</sup>	ISE 13.2 v1.07
XC6SLX9	ISE 12.4 v1.15	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.3 v1.12 <sup>(5)</sup>	ISE 13.2 v1.07
XC6SLX16	ISE 12.1 v1.08	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 11.5 v1.06	ISE 13.2 v1.07
XC6SLX25	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.2 v1.07
XC6SLX25T	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	N/A
XC6SLX45	ISE 12.1 v1.08	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 11.5 v1.07	ISE 13.1 v1.06
XC6SLX45T	ISE 12.1 v1.08	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.1 v1.08	N/A
XC6SLX75	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.2 v1.07
XC6SLX75T	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	N/A
XC6SLX100	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 v1.06
XC6SLX100T	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	N/A
XC6SLX150	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 v1.06
XC6SLX150T	ISE 12.2 v1.11 <sup>(6)</sup>	ISE 13.1 Update v1.18 <sup>(7)</sup>	ISE 12.2 v1.11 <sup>(6)</sup>	N/A
XA6SLX4	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX9	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX16	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX100	N/A	N/A	ISE 13.3 v1.20	N/A



Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T <sub>IOPI</sub>				T <sub>IOOP</sub>				T <sub>IOTP</sub>				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>	-3	-3N	-2	-1L <sup>(1)</sup>	
LVC MOS12, Fast, 2 mA	0.91	1.03	1.16	1.51	3.46	3.60	3.80	4.44	3.46	3.60	3.80	4.44	ns
LVC MOS12, Fast, 4 mA	0.91	1.03	1.16	1.51	2.35	2.49	2.69	3.30	2.35	2.49	2.69	3.30	ns
LVC MOS12, Fast, 6 mA	0.91	1.03	1.16	1.51	1.79	1.93	2.13	2.75	1.79	1.93	2.13	2.75	ns
LVC MOS12, Fast, 8 mA	0.91	1.03	1.16	1.51	1.68	1.82	2.02	2.64	1.68	1.82	2.02	2.64	ns
LVC MOS12, Fast, 12 mA	0.91	1.03	1.16	1.51	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
LVC MOS12_JEDEC, QUIETIO, 2 mA	1.50	1.62	1.75	1.88	6.39	6.53	6.73	7.31	6.39	6.53	6.73	7.31	ns
LVC MOS12_JEDEC, QUIETIO, 4 mA	1.50	1.62	1.75	1.88	4.98	5.12	5.32	5.88	4.98	5.12	5.32	5.88	ns
LVC MOS12_JEDEC, QUIETIO, 6 mA	1.50	1.62	1.75	1.88	4.67	4.81	5.01	5.54	4.67	4.81	5.01	5.54	ns
LVC MOS12_JEDEC, QUIETIO, 8 mA	1.50	1.62	1.75	1.88	4.23	4.37	4.57	5.22	4.23	4.37	4.57	5.22	ns
LVC MOS12_JEDEC, QUIETIO, 12 mA	1.50	1.62	1.75	1.88	3.99	4.13	4.33	4.94	3.99	4.13	4.33	4.94	ns
LVC MOS12_JEDEC, Slow, 2 mA	1.50	1.62	1.75	1.88	5.00	5.14	5.34	5.90	5.00	5.14	5.34	5.90	ns
LVC MOS12_JEDEC, Slow, 4 mA	1.50	1.62	1.75	1.88	2.85	2.99	3.19	3.80	2.85	2.99	3.19	3.80	ns
LVC MOS12_JEDEC, Slow, 6 mA	1.50	1.62	1.75	1.88	2.76	2.90	3.10	3.72	2.76	2.90	3.10	3.72	ns
LVC MOS12_JEDEC, Slow, 8 mA	1.50	1.62	1.75	1.88	2.35	2.49	2.69	3.30	2.35	2.49	2.69	3.30	ns
LVC MOS12_JEDEC, Slow, 12 mA	1.50	1.62	1.75	1.88	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns
LVC MOS12_JEDEC, Fast, 2 mA	1.50	1.62	1.75	1.88	3.46	3.60	3.80	4.42	3.46	3.60	3.80	4.42	ns
LVC MOS12_JEDEC, Fast, 4 mA	1.50	1.62	1.75	1.88	2.35	2.49	2.69	3.31	2.35	2.49	2.69	3.31	ns
LVC MOS12_JEDEC, Fast, 6 mA	1.50	1.62	1.75	1.88	1.79	1.93	2.13	2.76	1.79	1.93	2.13	2.76	ns
LVC MOS12_JEDEC, Fast, 8 mA	1.50	1.62	1.75	1.88	1.69	1.83	2.03	2.65	1.69	1.83	2.03	2.65	ns
LVC MOS12_JEDEC, Fast, 12 mA	1.50	1.62	1.75	1.88	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns

**Notes:**

1. The -1L values listed in this table are also applicable to the Spartan-6Q devices.
2. Devices with a -1L speed grade do not support Xilinx PCI IP.

Table 34: SSO Limit per V<sub>CCO</sub>/GND Pair

V <sub>CCO</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CCO</sub> /GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
1.2V	LVCMOS12, LVCMOS12_JEDEC	2	Fast	30 (1)	35	30	35
			Slow	51	55	51	52
			QuietIO	71	58	71	70
		4	Fast	17	17	17	19
			Slow	23	25	23	22
			QuietIO	35	32	35	32
		6	Fast	13	15	13	14
			Slow	19	20	19	17
			QuietIO	26	24	26	24
		8	Fast	N/A	12	N/A	12
			Slow	N/A	15	N/A	13
			QuietIO	N/A	20	N/A	19
		12	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	5
			QuietIO	N/A	11	N/A	10

Table 34: SSO Limit per V<sub>CCO</sub>/GND Pair (Cont'd)

V <sub>CCO</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CCO</sub> /GND Pair					
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324			
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5		
1.8V	LVCMOS18, LVCMOS18_JEDEC	2	Fast	39	46	39	47		
			Slow	65	75	65	74		
			QuietIO	80	80	80	85		
		4	Fast	22	25	22	25		
			Slow	38	36	38	29		
			QuietIO	45	40	45	35		
		6	Fast	16	18	16	17		
			Slow	27	25	27	19		
			QuietIO	30	28	30	23		
		8	Fast	13	15	13	14		
			Slow	16	18	16	16		
			QuietIO	25	22	25	18		
		12	Fast	5	7	5	5		
			Slow	7	8	7	6		
			QuietIO	11	10	11	8		
		16	Fast	4	5	4	4		
			Slow	7	8	7	5		
			QuietIO	11	10	11	8		
		24	Fast	N/A	5	N/A	3		
			Slow	N/A	8	N/A	8		
			QuietIO	N/A	10	N/A	8		
		HSTL_I_18				9	10	9	9
		HSTL_II_18				N/A	5	N/A	6
		HSTL_III_18				9	10	9	11
	DIFF_HSTL_I_18				27	30	27	27	
	DIFF_HSTL_II_18				N/A	15	N/A	18	
DIFF_HSTL_III_18				27	30	27	33		
MOBILE_DDR <sup>(3)</sup>				12	14	12	14		
DIFF_MOBILE_DDR <sup>(3)</sup>				36	42	36	42		
SSTL_18_I <sup>(3)</sup>				9	10	9	10		
SSTL_18_II <sup>(3)</sup>				N/A	5	N/A	4		
DIFF_SSTL_18_I <sup>(3)</sup>				27	30	27	30		
DIFF_SSTL_18_II <sup>(3)</sup>				N/A	15	N/A	12		

Table 34: SSO Limit per V<sub>CCO</sub>/GND Pair (Cont'd)

V <sub>CCO</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CCO</sub> /GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
2.5V	LVCMOS25	2	Fast	38	43	38	43
			Slow	46	52	46	48
			QuietIO	57	64	57	59
		4	Fast	21	24	21	23
			Slow	26	31	26	27
			QuietIO	33	32	33	30
		6	Fast	15	17	15	16
			Slow	19	22	19	19
			QuietIO	25	23	25	19
		8	Fast	12	15	12	14
			Slow	15	18	15	16
			QuietIO	21	19	21	16
		12	Fast	1	3	1	1
			Slow	2	7	2	4
			QuietIO	3	8	3	8
		16	Fast	1	3	1	1
			Slow	3	7	3	3
			QuietIO	4	9	4	8
		24	Fast	N/A	3	N/A	1
			Slow	N/A	5	N/A	2
QuietIO	N/A		8	N/A	6		
SSTL_2_I <sup>(3)</sup>				10	11	10	11
SSTL_2_II <sup>(3)</sup>				N/A	7	N/A	7
DIFF_SSTL_2_I <sup>(3)</sup>				30	33	30	33
DIFF_SSTL_2_II <sup>(3)</sup>				N/A	21	N/A	24

Table 34: SSO Limit per V<sub>CC0</sub>/GND Pair (Cont'd)

V <sub>CC0</sub>	I/O Standard	Drive	Slew	SSO Limit per V <sub>CC0</sub> /GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
3.3V	LVCMOS33	2	Fast	42	46	42	44
			Slow	50	55	50	49
			QuietIO	60	68	60	60
		4	Fast	21	27	21	25
			Slow	32	37	32	32
			QuietIO	39	42	39	37
		6	Fast	14	19	14	17
			Slow	19	25	19	22
			QuietIO	29	30	29	25
		8	Fast	11	15	11	14
			Slow	15	20	15	18
			QuietIO	25	24	25	20
		12	Fast	1	3	1	1
			Slow	2	5	2	2
			QuietIO	4	9	4	7
		16	Fast	1	2	1	1
			Slow	1	5	1	1
			QuietIO	3	10	3	8
		24	Fast	1	2	1	1
			Slow	2	5	2	1
			QuietIO	7	9	7	7

## Input/Output Logic Switching Characteristics

Table 35: ILOGIC2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Setup/Hold</b>						
$T_{ICE0CK}/T_{ICKCE0}$	CE0 pin Setup/Hold with respect to CLK	0.56/ -0.30	0.56/ -0.25	0.79/ -0.22	1.21/ -0.52	ns
$T_{ISRCK}/T_{ICKSR}$	SR pin Setup/Hold with respect to CLK	0.74/ -0.23	0.74/ -0.22	0.98/ -0.20	1.31/ -0.45	ns
$T_{IDOCK}/T_{IOCKD}$	D pin Setup/Hold with respect to CLK without Delay	1.19/ -0.83	1.36/ -0.83	1.73/ -0.83	2.18/ -1.77	ns
$T_{IDOCKD}/T_{IOCKDD}$	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	0.31/ 0.00	0.47/ 0.00	0.54/ 0.00	0.63/ -0.39	ns
<b>Combinatorial</b>						
$T_{IDI}$	D pin to O pin propagation delay, no Delay	0.95	1.28	1.53	2.25	ns
$T_{IDID}$	DDLY pin to O pin propagation delay (using IODELAY2)	0.23	0.39	0.44	0.74	ns
<b>Sequential Delays</b>						
$T_{IDLO}$	D pin to Q pin using flip-flop as a latch without Delay	1.56	1.86	2.39	3.49	ns
$T_{IDLOD}$	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY2)	0.68	0.97	1.20	1.94	ns
$T_{ICKQ}$	CLK to Q outputs for XC devices	1.03	1.24	1.43	2.11	ns
	CLK to Q outputs for XA and XQ devices	1.38	N/A	1.78	2.11	ns
$T_{RQ\_ILOGIC2}$	SR pin to Q outputs	1.81	1.81	2.50	3.05	ns

Table 36: OLOGIC2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>Setup/Hold</b>						
$T_{ODCK}/T_{OOCKD}$	D1/D2 pins Setup/Hold with respect to CLK	0.81/ -0.05	0.86/ -0.05	1.18/ 0.00	1.73/ -0.27	ns
$T_{OOCECK}/T_{OOCKOCE}$	OCE pin Setup/Hold with respect to CLK	0.75/ -0.10	0.75/ -0.10	1.01/ -0.05	1.66/ -0.23	ns
$T_{OSRCK}/T_{OOCKSR}$	SR pin Setup/Hold with respect to CLK	0.70/ -0.28	0.79/ -0.28	1.03/ -0.23	1.39/ -0.47	ns
$T_{OTCK}/T_{OOCKT}$	T1/T2 pins Setup/Hold with respect to CLK	0.24/ -0.08	0.56/ -0.06	0.83/ -0.01	0.99/ -0.19	ns
$T_{OTCECK}/T_{OOCKTCE}$	TCE pin Setup/Hold with respect to CLK	0.58/ -0.06	0.72/ -0.06	1.18/ -0.01	1.51/ -0.13	ns
<b>Sequential Delays</b>						
$T_{OOCKQ}$	CLK to OQ/TQ out for XC devices	0.48	0.51	0.74	0.74	ns
	CLK to OQ/TQ out for XA and XQ devices	0.85	N/A	1.16	0.74	ns
$T_{RQ\_OLOGIC2}$	SR pin to OQ/TQ out	1.81	1.81	2.50	3.05	ns

Table 47: Configuration Switching Characteristics<sup>(1)</sup> (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
<b>BPI Master Flash Mode Programming Switching<sup>(4)</sup></b>						
T <sub>BPICCO</sub> <sup>(5)</sup>	A[25:0], FCS_B, FOE_B, FWE_B, LDC outputs valid after CCLK falling edge	15	15	15	20	ns, Max
T <sub>BPIICCK</sub>	Master BPI CCLK (output) delay	10/100	10/100	10/100	10/130	μs, Min/Max
T <sub>BPIDCC</sub> /T <sub>BPICCD</sub>	Setup/Hold on D[15:0] data input pins	5.0/1.0	5.0/1.0	5.0/1.0	6.0/2.0	ns, Min
<b>SPI Master Flash Mode Programming Switching<sup>(6)</sup></b>						
T <sub>SPIDCC</sub> /T <sub>SPIDCCD</sub>	DIN, MISO0, MISO1, MISO2, MISO3, Setup/Hold before/after the rising CCLK edge	5.0/1.0	5.0/1.0	5.0/1.0	7.0/1.0	ns, Min
T <sub>SPIICCK</sub>	Master SPI CCLK (output) delay	0.4/7.0	0.4/7.0	0.4/7.0	0.4/10.0	μs, Min/Max
T <sub>SPICCM</sub>	MOSI clock to out	13	13	13	19	ns, Max
T <sub>SPICCFC</sub>	CSO_B clock to out	16	16	16	26	ns, Max
<b>CCLK Output (Master Modes)</b>						
T <sub>MCCKL</sub>	Master CCLK clock duty cycle Low	40/60				%, Min/Max
T <sub>MCCKH</sub>	Master CCLK clock duty cycle High	40/60				%, Min/Max
F <sub>MCCK</sub>	Maximum frequency, serial mode (Master Serial/SPI) All devices	40	40	40	30	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX9, LX16, LX25, LX25T, LX45, LX45T, LX75, and LX75T	40	40	40	25	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX100 and LX100T in x8 mode, LX150, and LX150T	40	40	40	20	MHz, Max
	Maximum frequency, parallel mode (Master SelectMAP/BPI) LX100 and LX100T in x16 mode	35	35	35	20	MHz, Max
F <sub>MCCKTOL</sub>	Frequency Tolerance, master mode	±50	±50	±50	±50	%
<b>CCLK Input (Slave Modes)</b>						
T <sub>SCCKL</sub>	Slave CCLK clock minimum Low time	5	5	5	8	ns, Min
T <sub>SCCKH</sub>	Slave CCLK clock minimum High time	5	5	5	8	ns, Min
<b>USERCCLK Input</b>						
T <sub>USERCCLKL</sub>	USERCCLK clock minimum Low time	12	12	12	16	ns, Min
T <sub>USERCCLKH</sub>	USERCCLK clock minimum High time	12	12	12	16	ns, Min
F <sub>USERCCLK</sub>	Maximum USERCCLK frequency	40	40	40	30	MHz, Max

**Notes:**

- Maximum frequency and setup/hold timing parameters are for 3.3V and 2.5V configuration voltages.
- To support longer delays in configuration, use the design solutions described in [UG380: Spartan-6 FPGA Configuration User Guide](#).
- [Table 6](#) specifies the power supply ramp time.
- BPI mode is not supported in:
  - LX4, LX25, or LX25T devices
  - LX9 devices in the TQG144 package
  - LX9 or LX16 devices in the CPG196 package.
- Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
- Defense-grade Spartan-6Q -2Q devices configure in single default SPI Master (x1) mode at T<sub>j</sub> = -55°C. During operation and when using all other configuration functions, the minimum operating temperature is -40°C.

## DCM Switching Characteristics

Table 53: Operating Frequency Ranges and Conditions for the Delay-Locked Loop (DLL)<sup>(1)</sup>

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
<b>Input Frequency Ranges</b>										
CLKIN_FREQ_DLL	Frequency of the CLKIN clock input when the CLKDV output is not used.	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	250 <sup>(3)</sup>	5 <sup>(2)</sup>	175 <sup>(3)</sup>	MHz
	Frequency of the CLKIN clock input when using the CLKDV output.	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	280 <sup>(3)</sup>	5 <sup>(2)</sup>	250 <sup>(3)</sup>	5 <sup>(2)</sup>	133 <sup>(3)</sup>	MHz
<b>Input Pulse Requirements</b>										
CLKIN_PULSE	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL < 150 MHz	40	60	40	60	40	60	40	60	%
	CLKIN pulse width as a percentage of the CLKIN period for CLKIN_FREQ_DLL > 150 MHz	45	55	45	55	45	55	45	55	%
<b>Input Clock Jitter Tolerance and Delay Path Variation<sup>(4)</sup></b>										
CLKIN_CYC_JITT_DLL_LF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL < 150 MHz	–	±300	–	±300	–	±300	–	±300	ps
CLKIN_CYC_JITT_DLL_HF	Cycle-to-cycle jitter at the CLKIN input for CLKIN_FREQ_DLL > 150 MHz.	–	±150	–	±150	–	±150	–	±150	ps
CLKIN_PER_JITT_DLL	Period jitter at the CLKIN input.	–	±1	–	±1	–	±1	–	±1	ns
CLKFB_DELAY_VAR_EXT	Allowable variation of the off-chip feedback delay from the DCM output to the CLKFB input.	–	±1	–	±1	–	±1	–	±1	ns

**Notes:**

1. DLL specifications apply when using any of the DLL outputs: CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, or CLKDV.
2. When operating independently of the DLL, the DFS supports lower CLKIN\_FREQ\_DLL frequencies. See Table 55.
3. The CLKIN\_DIVIDE\_BY\_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F<sub>MAX</sub> (see Table 48 and Table 49 for BUFG and BUFIO2 limits). When used with CLK\_FEEDBACK=2X, the input clock frequency matches the frequency for CLK2X, and is limited to CLKOUT\_FREQ\_2X.
4. CLKIN\_FREQ\_DLL input jitter beyond these limits can cause the DCM to lose LOCK, indicated by the LOCKED output deasserting. The user must then reset the DCM.
5. When using both DCMs in a CMT, both DCMs must be LOCKED.



Table 56: Switching Characteristics for the Digital Frequency Synthesizer (DFS) for DCM\_SP<sup>(1)</sup>

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
<b>Output Frequency Ranges</b>										
CLKOUT_FREQ_FX	Frequency for the CLKFX and CLKFX180 outputs	5	375	5	375	5	333	5	200	MHz
<b>Output Clock Jitter<sup>(2)(3)</sup></b>										
CLKOUT_PER_JITT_FX	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN < 20 MHz	Use the Clocking Wizard								ps
	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN > 20 MHz	Typical = ±(1% of CLKFX period + 100)								ps
<b>Duty Cycle<sup>(4)(5)</sup></b>										
CLKOUT_DUTY_CYCLE_FX	Duty cycle precision for the CLKFX and CLKFX180 outputs including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±(1% of CLKFX period + 350)								ps
<b>Phase Alignment<sup>(5)</sup></b>										
CLKOUT_PHASE_FX	Phase offset between the DFS CLKFX output and the DLL CLK0 output when both the DFS and DLL are used	-	±200	-	±200	-	±200	-	±250	ps
CLKOUT_PHASE_FX180	Phase offset between the DFS CLKFX180 output and the DLL CLK0 output when both the DFS and DLL are used	Maximum = ±(1% of CLKFX period + 200)								ps
<b>LOCKED Time</b>										
LOCK_FX <sup>(2)</sup>	When FCLKIN < 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	-	5	-	5	-	5	-	5	ms
	When FCLKIN > 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	-	0.45	-	0.45	-	0.45	-	0.60	ms

**Notes:**

1. The values in this table are based on the operating conditions described in Table 2 and Table 55.
2. For optimal jitter tolerance and a faster LOCK time, use the CLKIN\_PERIOD attribute.
3. Output jitter is characterized with no input jitter. Output jitter strongly depends on the environment, including the number of SSOs, the output drive strength, CLB utilization, CLB switching activities, switching frequency, power supply, and PCB design. The actual maximum output jitter depends on the system application.
4. The CLKFX, CLKFXDV, and CLKFX180 outputs have a duty cycle of approximately 50%.
5. Some duty cycle and alignment specifications include a percentage of the CLKFX output period. For example, this data sheet specifies a maximum CLKFX jitter of ±(1% of CLKFX period + 200 ps). Assuming that the CLKFX output frequency is 100 MHz, the equivalent CLKFX period is 10 ns, and 1% of 10 ns is 0.1 ns or 100 ps. Accordingly, the maximum jitter is ±(100 ps + 200 ps) = ±300 ps.

## Spartan-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 63 through Table 69. Values are expressed in nanoseconds unless otherwise noted.

Table 63: Global Clock Input to Output Delay Without DCM or PLL

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> DCM or PLL							
T <sub>ICKOF</sub>	Global Clock and OUTFF <i>without</i> DCM or PLL	XC6SLX4	6.12	N/A	7.68	9.41	ns
		XC6SLX9	6.12	6.51	7.68	9.41	ns
		XC6SLX16	5.98	6.42	7.48	9.10	ns
		XC6SLX25	6.20	6.69	7.84	9.44	ns
		XC6SLX25T	6.20	6.69	7.84	N/A	ns
		XC6SLX45	6.37	6.88	8.10	9.61	ns
		XC6SLX45T	6.37	6.88	8.10	N/A	ns
		XC6SLX75	6.39	6.99	8.16	10.18	ns
		XC6SLX75T	6.39	6.99	8.16	N/A	ns
		XC6SLX100	6.59	7.18	8.41	10.31	ns
		XC6SLX100T	6.59	7.18	8.41	N/A	ns
		XC6SLX150	6.98	7.68	8.80	10.62	ns
		XC6SLX150T	6.98	7.68	8.80	N/A	ns
		XA6SLX4	6.44	N/A	7.68	N/A	ns
		XA6SLX9	6.44	N/A	7.68	N/A	ns
		XA6SLX16	6.30	N/A	7.48	N/A	ns
		XA6SLX25	6.52	N/A	7.84	N/A	ns
		XA6SLX25T	6.52	N/A	7.84	N/A	ns
		XA6SLX45	6.69	N/A	8.12	N/A	ns
		XA6SLX45T	6.69	N/A	8.12	N/A	ns
		XA6SLX75	6.89	N/A	8.16	N/A	ns
		XA6SLX75T	6.89	N/A	8.16	N/A	ns
		XA6SLX100	N/A	N/A	8.36	N/A	ns
XQ6SLX75	N/A	N/A	8.16	10.18	ns		
XQ6SLX75T	6.89	N/A	8.16	N/A	ns		
XQ6SLX150	N/A	N/A	8.80	10.62	ns		
XQ6SLX150T	7.61	N/A	8.80	N/A	ns		

**Notes:**

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 74: Global Clock Setup and Hold With PLL in System-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
<b>Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.<sup>(1)</sup></b>							
T <sub>PSPLL</sub> / T <sub>PHPLL</sub>	No Delay Global Clock and IFF <sup>(2)</sup> with PLL in System-Synchronous Mode	XC6SLX4	1.37/0.25	N/A	1.52/0.41	2.07/0.69	ns
		XC6SLX9	1.37/0.21	1.48/0.21	1.52/0.26	2.07/0.69	ns
		XC6SLX16	1.33/-0.03	1.53/-0.02	1.60/-0.02	1.57/0.48	ns
		XC6SLX25	1.65/0.28	1.71/0.28	1.91/0.28	2.44/0.76	ns
		XC6SLX25T	1.65/0.28	1.71/0.28	1.91/0.28	N/A	ns
		XC6SLX45	1.55/0.18	1.64/0.18	1.75/0.18	2.02/0.90	ns
		XC6SLX45T	1.55/0.18	1.64/0.18	1.75/0.18	N/A	ns
		XC6SLX75	1.77/0.21	1.89/0.21	2.13/0.21	2.46/0.53	ns
		XC6SLX75T	1.77/0.21	1.89/0.21	2.13/0.21	N/A	ns
		XC6SLX100	1.44/0.32	1.52/0.32	1.70/0.32	1.78/0.86	ns
		XC6SLX100T	1.44/0.32	1.52/0.32	1.70/0.32	N/A	ns
		XC6SLX150	1.39/0.49	1.48/0.49	1.67/0.49	1.94/0.94	ns
		XC6SLX150T	1.39/0.49	1.48/0.49	1.67/0.49	N/A	ns
		XA6SLX4	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX9	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX16	1.89/-0.08	N/A	1.72/-0.08	N/A	ns
		XA6SLX25	1.85/0.16	N/A	2.08/0.16	N/A	ns
		XA6SLX25T	1.85/0.16	N/A	2.17/0.16	N/A	ns
		XA6SLX45	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX45T	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX75	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX100	N/A	N/A	2.34/0.14	N/A	ns
		XQ6SLX75	N/A	N/A	2.25/0.06	2.46/0.53	ns
		XQ6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XQ6SLX150	N/A	N/A	1.79/0.37	1.94/0.94	ns
XQ6SLX150T	1.43/0.37	N/A	1.79/0.37	N/A	ns		

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Date	Version	Description of Revisions
06/14/10	1.5	<p>In <a href="#">Table 2</a>, added note 5 and added temperature range to <math>V_{FS}</math> and <math>R_{FUSE}</math>. Removed speed grade delineation, revised <math>I_{RPD}</math> description, and updated note 2 in <a href="#">Table 4</a>. Added note 2 to <a href="#">Table 7</a>. Added DIFF_MOBILE_DDR to <a href="#">Table 8</a> and <a href="#">Table 10</a>. Added note 4 to <a href="#">Table 15</a>. Changed minimum <math>DV_{PPIN}</math> in <a href="#">Table 16</a>. Updated <math>F_{GTPDRPCLK}</math> in <a href="#">Table 19</a>. Increased maximum <math>T_{LLSKEW}</math> in <a href="#">Table 22</a>. Updated descriptions and added data to <a href="#">Table 23</a>. Removed note 1 and added new data to the Networking Applications section in <a href="#">Table 25</a>. Updated <a href="#">Table 26</a> and <a href="#">Table 27</a> to the data in ISE v12.1 software with speed specification v1.08. In <a href="#">Table 28</a>, added DIFF_MOBILE_DDR and updated -4 speed grade data. Updated the maximum I/O pairs per bank in <a href="#">Table 33</a>. Updated note 2 on <a href="#">Table 39</a>. Revised the <math>F_{MAX}</math> in <a href="#">Table 44</a>. In <a href="#">Table 47</a>, updated description for <math>T_{SMCKCSO}</math>, revised values for <math>T_{POR}</math> and added Min value, added <math>T_{BPIICCK}</math> and <math>T_{SPIICCK}</math>. Also in <a href="#">Table 47</a>, added device dependencies to <math>F_{SMCCK}</math> and <math>F_{RBCKK}</math>. Updated and added data to <a href="#">Table 63</a> through <a href="#">Table 78</a>, and <a href="#">Table 81</a>. In <a href="#">Table 79</a>, added data on the XC6SLX45-FG(G)676 and revised the XC6SLX45T and XC6SLX150T values.</p> <p>The following changes to this specification are addressed in the product change notice <a href="#">XCN10024</a>, <i>MCB Performance and JTAG Revision Code for Spartan-6 LX16 and LX45 FPGAs</i>. In <a href="#">Table 2</a>, revised the <math>V_{CCINT}</math> to add the memory controller block extended performance specifications. In <a href="#">Table 25</a>, changed the standard specifications and added extended performance specifications for the memory controller block and note 2. Added note 4 and updated values in <a href="#">Table 34</a>.</p>
06/24/10	1.6	<p>Production release of XC6SLX45T (-2 and -3 speed grades), XC6SLX16 and XC6SLX45 (-3 speed grade) devices which includes changes to <a href="#">Table 26</a> and <a href="#">Table 27</a> (ISE v12.1 software with speed specification v1.08).</p> <p>Added the -3N speed grade, which designates Spartan-6 devices that do not support MCB functionality. This includes changes to <a href="#">Table 2</a> (note 2), <a href="#">Table 25</a> (note 4), and <a href="#">Switching Characteristics</a> (<a href="#">Table 26</a>).</p> <p>Updated <a href="#">Simultaneously Switching Outputs</a> discussion. Added -3 speed grade values for <math>T_{TAP}</math> and <math>F_{MINCAL}</math> values in <a href="#">Table 39</a>. In <a href="#">Table 40</a>, updated <math>T_{RPW}</math> (-2 and -3 speed grade) values and <math>F_{TOG}</math> (-3 speed grade) values. In <a href="#">Table 48</a>, updated <math>T_{GIO}</math> (-2 and -3 speed grade) values. Updated -3 values in spread spectrum section of <a href="#">Table 57</a>.</p>
07/16/10	1.7	<p>Production release of specific devices listed in <a href="#">Table 26</a> and <a href="#">Table 27</a> using ISE v12.2 software with speed specification v1.11. Added note 4 advising designers of the patch which contains v1.11. Also updated the -1L speed specification to v1.04. Updated numerous -4 and -1L values. Added -4 <math>T_{TAP}</math> values and <math>F_{MINCAL}</math> to <a href="#">Table 39</a>. Revised <math>T_{CINCK}/T_{CKCIN}</math> in <a href="#">Table 40</a>. In <a href="#">Table 41</a>, revised <math>T_{SHCKO}</math>. In <a href="#">Table 42</a>, revised <math>T_{REG}</math>. Added new -1L values to <a href="#">Table 47</a>. Added and updated values in <a href="#">Table 79</a>.</p>
07/26/10	1.8	<p>Production release of XC6SLX25, XC6SLX25T, XC6SLX100 and XC6SLX100T in the specific speed grades listed in <a href="#">Table 26</a> and <a href="#">Table 27</a> using ISE v12.2 software with speed specification v1.11. Added note 7 to <a href="#">Table 2</a> and moved <math>V_{FS}</math> and <math>R_{FUSE}</math> to a new <a href="#">Table 3</a>. Added <math>I_{HS}</math> and note 4 to <a href="#">Table 4</a>. Added note 1 to <a href="#">Table 28</a>. Added and updated SSO limits per <math>V_{CC0}/GND</math> pairs in <a href="#">Table 34</a>. Added note 3 to <a href="#">Table 47</a>. In <a href="#">Table 54</a>, removed -1L specifications for CLKOUT_PER_JITT_DV1/2 and revised CLKIN_CLKFB_PHASE and CLKOUT_PHASE_DLL values. Updated note 3 in both <a href="#">Table 56</a> and <a href="#">Table 57</a>.</p>
08/23/10	1.9	<p>Updated values for <math>F_{GTPRANGE1}</math>, <math>F_{GTPRANGE2}</math>, and <math>F_{GPLLMIN}</math> in <a href="#">Table 18</a>. Revised -3 and -4 values in <a href="#">Table 21</a>. Removed the -1L speed grade readback support restriction and note 3 in <a href="#">Table 47</a>.</p>
11/05/10	1.10	<p>Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in <a href="#">Table 26</a> and <a href="#">Table 27</a> using ISE v12.3 software with speed specification v1.12 for the -2 speed grade available in the 12.3 <i>Speed Files Patch</i>. Added note 3 advising designers of the patch which contains v1.12.</p> <p>In <a href="#">Table 2</a>, added note 4. In <a href="#">Table 4</a>, added note 2. In <a href="#">Table 10</a>, added notes 2 and 3. In <a href="#">Table 44</a>, added note 2. In <a href="#">Table 47</a>, updated symbol for <math>T_{SMWCKK}/T_{SMCKKW}</math>, changed -1L values for <math>T_{USERCCLKH}</math> and <math>T_{USERCCLKL}</math>, and added and revised the modes for <math>F_{MCKK}</math> and <math>F_{SMCKK}</math>. In <a href="#">Table 53</a>, redefined and expanded description for CLKIN_FREQ_DLL and rewrote note 3. Updated title of <a href="#">Table 58</a>. Also in <a href="#">Table 78</a>, revised <math>T_{DCD\_CLK}</math> for XC6SLX150 and XC6SLX150T. Changed description of <math>T_{PSFD}/T_{PHFD}</math> in <a href="#">Table 71</a>.</p> <p>For the -1L speed grade, updated data sheet to ISE 12.3 software with speed specification v1.05 which revised the values in the following tables: <a href="#">Table 25</a>, <a href="#">Table 28</a>, <a href="#">Table 35</a>, <a href="#">Table 36</a>, <a href="#">Table 37</a>, <a href="#">Table 40</a> through <a href="#">Table 43</a>, <a href="#">Table 48</a> through <a href="#">Table 56</a>, <a href="#">Table 62</a> through <a href="#">Table 78</a>, <a href="#">Table 80</a>, and <a href="#">Table 81</a>. Updated <a href="#">Notice of Disclaimer</a>.</p>

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